Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/721,075	TANAKA, KOICHIRO	
Examiner	Art Unit	
M. Alexandra Elve	1725	

SEARCHED				
Class	Subclass	Date	Examiner	
update				
219	121.76	12/27/2005	MAE	
219	121.78	12/27/2005	MAE	
219	121.81	12/27/2005	MAE	
219	121.85	12/27/2005	MAE	
219	121.65	12/27/2005	MAE	
219	121.66	12/27/2005	MAE	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
update US OCR, US PAT, US PG, Derwent, JPO, EPO	12/27/2005	MAE		
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